

Notice of References Cited

Application/Control No.

10/550,842

Applicant(s)/Patent Under
Reexamination
CHUNG ET AL.

Examiner

Frederick J. Parker

Art Unit

1792

Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0025379	02-2002	Nakamura et al.	427/322
*	B	US-6,116,728	09-2000	Miyake et al.	347/102
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FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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